

March 2015 FDMS7678

# N-Channel Power Trench<sup>®</sup> MOSFET 30 V, 26 A, 5.5 m $\Omega$

#### **Features**

- Max  $r_{DS(on)} = 5.5 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 17.5 \text{ A}$
- Max  $r_{DS(on)} = 6.8 \text{ m}\Omega$  at  $V_{GS} = 4.5 \text{ V}$ ,  $I_D = 15 \text{ A}$
- High Performance Technology for Extremely Low r<sub>DS(on)</sub>
- Termination is Lead-Free
- RoHS Compliant

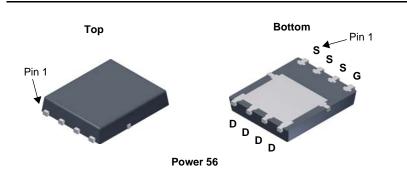
#### **General Description**

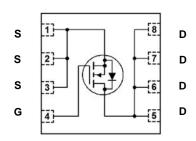
This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced Power Trench® process that has been especially tailored to minimize the on-state resistance. This device is well suited for Power Management and load switching applications common in Notebook Computers and Portable Battery Packs.

#### **Applications**

- DC DC Buck Converters
- Notebook Battery Power Management
- Load Switch in Notebook







# **MOSFET Maximum Ratings** $T_A = 25$ °C unless otherwise noted.

Symbol	Parameter	Ratings	Units		
$V_{DS}$	Drain to Source Voltage		30	V	
$V_{GS}$	Gate to Source Voltage	(Note 3	3) ±20	V	
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C	26	A	
	Drain Current -Continuous (Silicon limited)	T <sub>C</sub> = 25 °C	72		
ID	-Continuous	$T_A = 25 ^{\circ}\text{C}$ (Note 1a)	17.5	A	
	-Pulsed		70		
E <sub>AS</sub>	Single Pulse Avalanche Energy	(Note 4	54	mJ	
P <sub>D</sub>	Power Dissipation $T_C = 25 ^{\circ}\text{C}$		41	W	
	Power Dissipation $T_A = 25 ^{\circ}\text{C}$ (Note 1a)		2.3	VV	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Ra	-55 to +150	°C		

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS7678	FDMS7678	Power 56	13 "	12 mm	3000 units

# **Electrical Characteristics** $T_J = 25~^{\circ}\text{C}$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Units
Off Chara	acteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	30			V
BV <sub>DSSt</sub>	Drain to Source Breakdown Voltage (transient)	$V_{GS} = 0 \text{ V}, \ I_{D(aval)} = 14.2 \text{ A},$ $T_{case} = 25 \text{ °C}, \ t_{transient} = 10 \text{ ns}$	34			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		21		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24 V, V <sub>GS</sub> = 0 V			1	μΑ
$I_{GSS}$	Gate to Source Leakage Current, Forward	$V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

#### On Characteristics

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	1.2	1.5	3.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25 °C		-5		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 17.5 \text{ A}$		4.7	5.5	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 4.5 \text{ V}, I_D = 15 \text{ A}$		5.6	6.8	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 17.5 \text{ A T}_J = 125 ^{\circ}\text{C}$		6.3	7.4	
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = 5 V, I <sub>D</sub> = 17.5 A		90		S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 15 V, V <sub>GS</sub> = 0 V f = 1 MHz		1810	2410	pF
C <sub>oss</sub>	Output Capacitance			620	820	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			75	110	pF
R <sub>q</sub>	Gate Resistance		0.1	0.7	2.5	Ω

#### **Switching Characteristics**

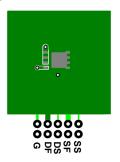
t <sub>d(on)</sub>	Turn-On Delay Time		10	19	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15 V, I <sub>D</sub> = 17.5 A	4	10	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	26	41	ns
t <sub>f</sub>	Fall Time		3	10	ns
Q <sub>g(TOT)</sub>	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V	28	39	nC
	Total Gate Charge	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $V_{DD} = 15 \text{ V}$	14	19	nC
$Q_{gs}$	Gate to Source Charge	I <sub>D</sub> = 17.5 A	4.4		nC
$Q_{gd}$	Gate to Drain "Miller" Charge		3.9		nC

#### **Drain-Source Diode Characteristics**

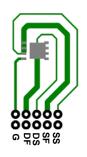
V <sub>SD</sub>	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 1.9 \text{ A}$ (Note 2)	0.7	1.2	V
	Source to Brain Blode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 17.5 \text{ A}$ (Note 2)	0.8	1.2	v
t <sub>rr</sub>	Reverse Recovery Time	I <sub>E</sub> = 17.5 A, di/dt = 100 A/μs	30	49	ns
Q <sub>rr</sub>	Reverse Recovery Charge	$-1$ F = 17.3 A, $\frac{1}{4}$	13	23	nC

#### NOTES

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b.125 °C/W when mounted on a minimum pad of 2 oz copper.

<sup>2.</sup> Pulse Test: Pulse Width < 300  $\mu\text{s},$  Duty cycle < 2.0 %.

<sup>3.</sup> As an N-ch device, the negative  $V_{GS}$  rating is for low duty cycle pulse occurence only. No continuous rating is implied.

<sup>4.</sup>  $E_{AS}$  of 54 mJ is based on starting  $T_J$  = 25 °C, L = 0.3 mH,  $I_{AS}$  = 19 A,  $V_{DD}$  = 27 V,  $V_{GS}$  = 10 V.

### **Typical Characteristics** $T_J = 25$ °C unless otherwise noted.

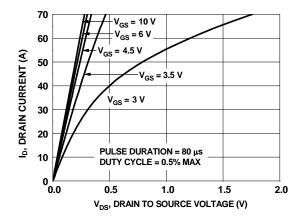


Figure 1. On Region Characteristics

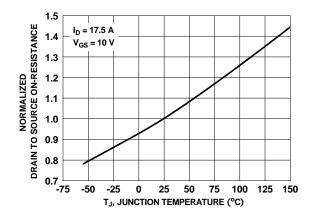


Figure 3. Normalized On Resistance vs. Junction Temperature

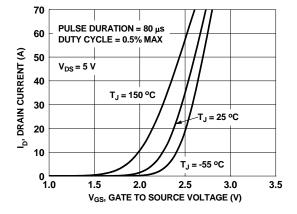


Figure 5. Transfer Characteristics

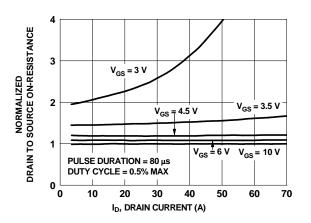


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

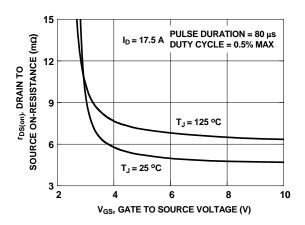


Figure 4. On-Resistance vs. Gate to Source Voltage

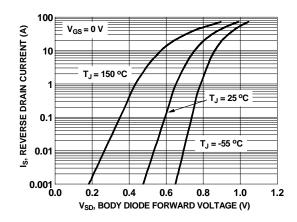


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

## **Typical Characteristics** $T_J = 25$ °C unless otherwise noted.

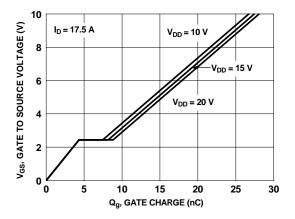


Figure 7. Gate Charge Characteristics

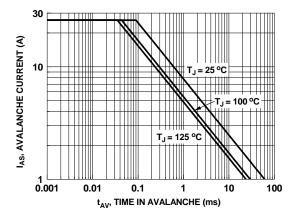


Figure 9. Unclamped Inductive Switching Capability

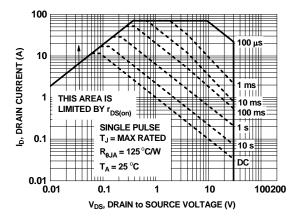


Figure 11. Forward Bias Safe Operating Area

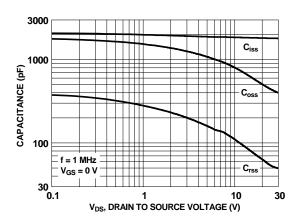


Figure 8. Capacitance vs. Drain to Source Voltage

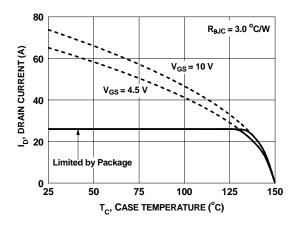


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

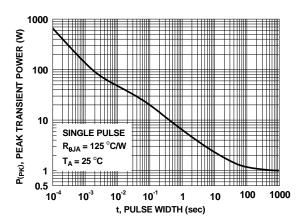


Figure 12. Single Pulse Maximum Power Dissipation

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted.

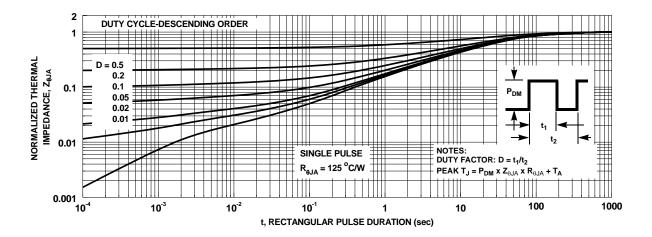
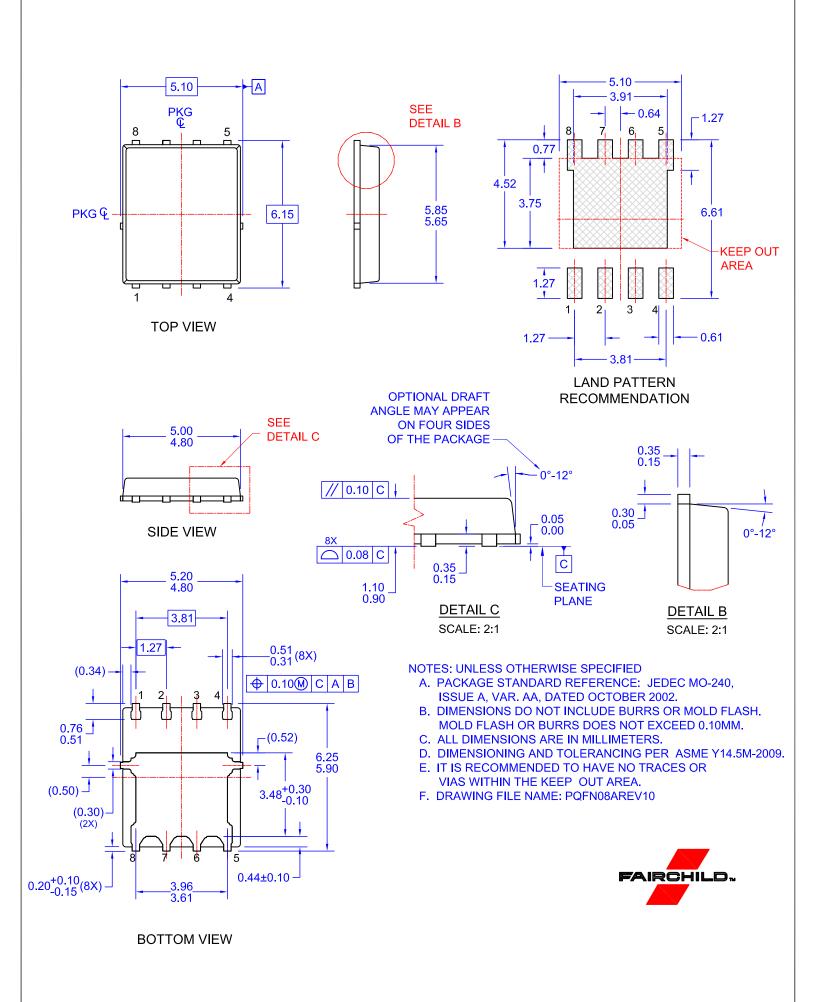


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



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